Approaches to Component Reliability in IEC Standards Development

NIST/UL Workshop on Photovoltaic Materials Durability

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Problem statement:

- Significant issues with degradation of polymeric materials observed with fielded modules
 - 61215/61730 testing does not address this issue well

Recognized:

- Stress test methods not well established for very long durability analysis, relevant to target service life
- Multi-stress exposures (sequential or combi) are missing
- Some analyses better done at component level
- Already too many test requirements...
- Not enough known to select one "right" test set



Inner/Outer Layer Yellowing



Outer Layer Cracking/Delam



Core Qualification Standards:

- IEC 61730 PV module safety qualification
- IEC 61215 PV modules Design qualification and type approval



IEC 61730 Stress Testing



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• Minimum BDVdc

Backsheet Defects in High Desert, SW USA

Total installation – single model number

- 100% BS cracking type A
- 100% BS cracking type B
- BS inner layer cracking type C
 - ~5% exhibited severe busbar corrosion
 - instances of electrical fires
- No obvious BS defects type D
- Encapsulant browning all modules







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Adding Component Testing:

IEC 62788 Series: Measurement procedures for materials used in photovoltaic modules

- 62788-1: Encapsulants
- 62788-2: Frontsheets and Backsheets
- 62788-5: Edge Seals
- 62788-7: Stress exposures

Components:

- IEC 62790 Junction Boxes for PV modules
- IEC 62852 Connectors for DC-application in PV systems
- IEC 62930 Electric cables for PV systems.

Post-stress evaluations in 62788-2 (Frontsheets/Backsheets)

UCF No.	Test Methods	Component evaluation	Package evaluation	Fresh	1 000 h DH test	2 000 h UV (Xenon) exposure (4.10.3)	
		<u>C</u> oupon <u>F</u> iltered Sheet	Minimodule		(4.10.2)	air side ^a	sun-facing side ^b
3	Tensile strength [MPa] (MD)	_		✓	✓	✓	✓
5	Tensile strength [MPa] (TD)	- S E	ΝΔ	✓	✓	0	0
А	Elongation at break [%] (MD)		NA	✓	✓	✓	✓
-	Elongation at break [%] (TD)			✓	✓	0	0
5	Bond strength between layers of composition – or weakest link [N/mm] (for peelable layers)	S,F	NA	\checkmark	✓	0	0
6	Bond strength between coatings or thin layers and film [rating scale] (for layers too thin or brittle to peel)	S,F	NA	\checkmark	✓	0	-
7	Bond strength between a specific encapsulant and sheet [N/mm]	С	Coupon (BS/E) Minimodule (E/Cell)	0	0	0	0
8	Bond strength between a specific JBox adhesive and BS (N/mm)		Refer to IEC 62790	0	IEC 62790	_	-
12	dc breakdown voltage [kV]			\checkmark	0	0	0
15	Visual inspection			\checkmark	✓	\checkmark	✓
16	Solar transmittance (for transmittive sheet only)			✓	0	0	0
17	Solar reflectance c(for reflective sheets only)			✓ (sun-facing)	O (sun- facing)	-	0
18	Yellowness index DYI c			0	0	0	0
19	CIE L*a*b* (D65/10°) c			0	0	0	0
20	Specular gloss c			0	0	0	0



Core Qualification Standards:

- IEC 61215 PV modules Design qualification and type approval
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IEC 61730 AMD1

- Will include requirements for component pre-qualifications:
 - IEC 62788-2-1 Safety Requirements for Frontsheets and backsheets
 - IEC 62790 Junction Boxes for PV modules
 - IEC 62852 Connectors for DC-application in PV systems
 - IEC 62930 Electric cables for PV systems).







No significant change in tensile strength after oven aging



TD Strain at Break (%) as a function of hrs at 120C



Alignment pre-CD 62788-2-1 with 61730-1 & -2

Update figure with layer stack schematics from 61730-1 AM1

Backsheet constructions and Relied-Upon Insulation (RUI)



Jürgen Jung / TC82 WG2 @ Mississauga / Ontario

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IEC 62788-2-1 Safety Requirements, Frontsheets and Backsheets Test Matrix

No.	Test name	Clause	final product (unexposed)	1000 h DH test clause 5.9.2 FBST 08	2000 h UV test clause 5.9.3 FBST 09
FBST 01	Visual inspection	5.2	YES (r, s)	YES	YES
FBST 02	Dimensions and tolerances [µm]	5.3	YES (r, s)	-	-
FBST 03	Distance through insulation [µm]	5.4	YES	-	_
FBST 04	TI or RTE (RTI) [°C] and thermal failsafe test (Elongation at break)	5.5	YES*	-	-
FBST 05	CTI test	5.6	YES	-	-
FBST 06	DC breakdown voltage	5.7	YES (s)	YES	YES
FBST 07	Tensile strength [MPa]	5.8	YES (s)	YES	YES
FBST 07	Elongation at break [%]	5.8	YES (s)	YES	YES

Note:

)* For FBST 04, tests are conducted on single layers, not on final product.



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Beyond qualification

- **IEC 63126**: Testing for High T applications
- **IEC 63209**: Extended testing of PV module for risk analysis
 - Part 1: Modules



IEC 63126: Testing for High T Applications

		Original Requirement	Proposal - Level 1	Proposal - Level 2	
Standard Test Ref Test Name		T 98% = 70 °C or less	<i>T</i> _{98%} > 70 °C to ≤ 80 °C	$T_{98\%} > 80 \ ^{\circ}C \ to \le 90 \ ^{\circ}C$	
IEC 61215		Hot-spot endurance test	(50 ± 10) °C	+10 °C, (60 ± 10) °C	+20 °C, (70 ± 10) °C
	MQT 10	UV preconditioning	(60 ± 5) °C	+10 °C, (70 ± 5) °C	+20 °C, (80 ± 5) °C
	MQT 11	Thermal cycling test	(85 ± 2) °C	+10 °C, (95 ± 2) °C	+20 °C, (105 ± 2) °C
	MQT 18	Bypass diode testing chamber	(75 ± 2) °C	+15 °C, (90 ± 2) °C	+25 °C, (100 ± 2) °C
		Part 1	Isc	1.15 * I _{SC} for diode T	1.15 * I _{sc} for diode T
		Part 2	1.25 * <i>I</i> _{SC}	1.4 * I _{SC} for stress	1.4 * I _{SC} for stress
IEC 61730		RTI/RTE/TI	min RTI 90 °C	min RTI 100°C	min RTI 110 °C
	MST 22	Hot spot endurance	(50 ± 10) °C	+10 °C, (60 ± 10) °C	+20 °C, (70 ± 10) °C
MST 37 Material creep MST 51 Thermal cycle		Material creep test	105 °C	no change	110 °C
		Thermal cycle	(85 ± 2) °C	+10 °C, (95 ± 2) °C	+20 °C, (105 ± 2) °C
MST 54 UV test		UV test	(60 ± 5) °C +10 °C, (70 ± 5) °C		+20 °C, (80 ± 5) °C
	MST 56	Dry heat conditioning	105 °C	no change	110 °C
IEC 62788-1-7 (encapsulant, performance)	8	Optical durability encapsulants	IEC TS 62788-7-2 (A3 cond.)	IEC TS 62788-7-2 (A4 c ond.)	IEC TS 62788-7-2 (A5 c ond.)
IEC TS 62788-2* (backsheet and frontsheet safety)	4.10.3	Weathering (UV) ageing test	IEC TS 62788-7-2 (A3 cond.)	IEC TS 62788-7-2 (A4 c ond.)	IEC TS 62788-7-2 (A5 c ond.)
IEC 62852		Marking, Upper Limit			
120 02002		Temperature (ULT)	no requirement	95 °C	105 °C
IEC 62790		Range of temperature (upper			
IEC 02/90		ambient temperature)	no requirement	95 °C	105 °C

63209 Extended testing of PV module for risk analysis Part 1 – Modules

	[5.2 Physical m	neasurement						
		5.3 Visual inspection	– IEC 61215 MQT 01						
5.4 Initial stabilization – IEC 61215 MQT 19.1 5.5 Performance at STC – IEC 61215 MQT 06.1 & 07				There is a general consensus that for extended UV exposure					
				It is more practical to test at the component or mini-module level than with full size modules. Users of extended test data					
		5.6 Insulation test –	IEC 61215 MQT 03	are encouraged to use extended coupon or mini-module tests					
		5.7 Wet leakage test -	- IEC 61215 MQT 15	to evaluate individual polymer components, and specific					
	[5.8 EL imaging – IEC 60	0904-13 (<u>lsc</u> , 0.1X <u>lsc</u>)	combinations of polymeric components					
		5.9 Insulation thickness te	est – IEC 61730 MST 04*						
6.3 Sequence 1	6.4 Sequence 2	6.5 Sequence 3a (UV on front)	6.6 Sequence 3b (UV on back)	6.7 Sequence 4 6.8 Sequence 5					
Thermal cycling (200 cycles) MQT 11 0119.206.1/70315 EL	Static load MQT 16 0119.206.1/70315EL	Damp heat (200 h) MQT 13 01 UV (60 kWh/m ²)	Damp heat (200 h) MQT 13 01 UV (60 kWh/m²)	Damp heat (1000 h) MQT 13 PID (+ and/or -) (96 h) IEC 62804 01 19.2 06.1/7 03 15 EL 01 19.2 06.1/7 03 15 EL					
Thermal cycling (200 cycles)	Cyclic load 1000 X @ 1000 Pa IEC 62782 01 19.2 06.1/7 03 15 EL	MQT 10MQT 100101Humidity Freeze (10 X) MQT 12Humidity Freeze (10 X) MQT 12	Damp heat (1000 h) PID (+ and/or -) (96 h) MOT 12 USE C 2004						
MQT 11 0119.206.1/70315EL			(10 X) MQT 12	0119.206.1/70315EL 0119.206.1/70315EL					
Thermal cycling	Thermal cycling	0119.206.1/7 0315EL	0119.206.1/7 0315EL						
(200 cycles)	MQT 11	00 (60 kWh/m2) MQT 10	UV (60 kWh/m2) MQT 10						
	0119.206.1/70315EL	01	01	Optionally, the items in					
0113200.177031311	Humidity Freeze (10 X) MQT 12	Thermal cycle (200 X) MQT 11	Thermal cycle (200 X) MQT 11	red may be repeated					
	0119.206.1/70315EL	0119.206.1/70315ELIT	0119.206.1/70315ELIT						



IEC 63209 Part 2: Durability characterization of polymeric component materials and packaging sets

Data for risk analysis some combination of test data from:

A.Component specific testing

B.BOM specific coupon testing

C.Minimodule AND/OR "structured coupon" testing

All possible tests for all different specimens is too much!

> Need to determine a set which allows for good analysis

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Considerations



I. Component level testing

- Utilizes test methods established in 62788 series (and Jbox,Connectors and Cables standards)
- Evaluation tests and specimen designs described in standards
- UV Stress exposures from 62788-7-2
 - Longer exposures to be included

		polymeric frontsheet	/backsheet	encapsulant					
stress:	DH UV front (A3)		UV back (A3)	DH	UV				
duration	1000 h 2000 h, 4000 h Optional: additional increments of 4000 h, up to 16000 h		2000 h, 4000 h	1000 h	4000 h Optional: additional increments of 4000 h, up to 16000 h				
targeted failure modes	 changes to key materials properties (potential early indicators); maintenance of key properties above minimum values 								
tests:	- color - tensile - Vdc BDV (d - adhesion y	opt) within the BS/FS		- transmissi - adhesion t	on o glass				



Test duration - Place holder for discussions



II – Polymeric packaging materials (specific BOM)

stress:	DH	UV front (A3)	UV back (A3)	Frontside Sequential	Backside Sequential	Adding combination stress	
duration	1000 h	2000 h, 4000 h2000 hSequential TesOptional: additional4000 hw/ long UV exincrements of 4000 h, upto 16000 hw/ long UV ex		Sequential Testing (TBD) w/ long UV exposure)	Sequential Testing, including UV, DH, TC - suggest MAST = DH/UV/TC/UV/TC/UV		
targeted failure modes	- loss of ad - changes	hesion in key material properties					
tests:	- visual (c - adhesior - glass - enca - othe	olor, delam) 1 to encapsulant psulant to backsheet er?					

Place holder for discussions:

- Exposure duration
- Sequential testing -





III – Minimodules (specific BOM)

	Materials stack w/ cells/wiring							
stress:	DH	Frontside Sequential Testing	Backside Sequential Testing, including UV. DH. TC - suggest MAST					
duration	1000h	TBD, include long UV	DH 1000					
		exposure	UV1000					
			3 x (TC200 + UV1000)					
targeted	delamination							
failure	backsheet cracks							
modes								
tests:	visual (color, cracks, delamination bubbles)							
	power output							
	?							

Adding stresses:

- 3D structure
- Voltage





Anticipated: multi-step approach

- Multiple components, multiple module designs can be considered not all at once
 - > Expect this may take multiple Parts
- ✤Path forward:
 - 1. Review of 62788 Series, Jbox, Connector and Cable standards
 - Consolidate exposures and testing into one document for "Risk Analysis" with 63209-1 data
 - Consider extended sequences
 - Consider new sequences (if easily agreed)
 - 2. Project Team to identify biggest gaps, and focus efforts; options:
 - Combined stress sequences
 - Adhesion testing
 - BOM-specific testing
 - Consider extended sequences
 - 3. Parallel test plans to help identify useful combinations of testing

Test Plan Sets

		Solder Bump Coupon		Flat Coupon			63209 front-	63209 back
		A3 expo	osures + TC	A	3 exposure	s	side seq	side seq
		FS						full size
	specimen	coupon+	BS coupon+	FS laminate	FS trm	BS film	1-cell m-mod	modules
	mat'l orientation	MD	MD and TD		TD only		MD (aligned to ribbon dir.)	
	Post-stress test	visual visual		visual	visual tensile	visual tensile	visual	visual
<u>BS</u>	prior observations							
	front side cracking							
PET1	reduction of %E	X	x	x	X	X	X	Z
PET2	yellowing, fs cracking	X	x	x	X	X	x	
PVDF1	back side cracking	X	x		X	X		
PVDF2	back side cracking	X	х		X	х		x
PVDF3	unknown	x	х		Х	х		
ТРТ	known good	X	х	x	Х	х	x	
TPE	known good							х
AAA	fs and bs cracking	X	X	X	X	Х	X	x
FEVE	front side cracking	x					x	





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